Power MOSFET, N-Channel, 600 V, 1.2 Ω

Features

- Low ON Resistance
- Low Gate Charge
- ESD Diode-Protected Gate
- 100% Avalanche Tested
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

ABSOLUTE MAXIMUM RATINGS ($T_C = 25^{\circ}C$ unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-to-Source Voltage	V_{DSS}	600	V
Continuous Drain Current, R _{0JC} (Note 1)	I _D	7.1	Α
Continuous Drain Current $T_A = 100^{\circ}C$, $R_{\theta JC}$ (Note 1)	Ι _D	4.5	Α
Pulsed Drain Current, V _{GS} @ 10 V	I _{DM}	28	Α
Power Dissipation, $R_{\theta JC}$	P_{D}	35	W
Gate-to-Source Voltage	V _{GS}	±30	٧
Single Pulse Avalanche Energy, L = 6.3 mH , $I_D = 6.0 \text{ A}$	E _{AS}	113	mJ
ESD (HBM) (JESD22-A114)	V _{esd}	3000	V
RMS Isolation Voltage (t = 0.3 sec., R.H. \leq 30%, T_A = 25°C) (Figure 13)	V _{ISO}	4500	V
Peak Diode Recovery (Note 2)	dv/dt	4.5	V/ns
MOSFET dV/dt	dV/dt	60	V/ns
Continuous Source Current (Body Diode)	I _S	6.0	Α
Maximum Temperature for Soldering Leads	T_L	260	°C
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

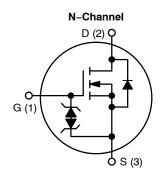
- Limited by maximum junction temperature
- 2. $I_{SD} = 6.0 \text{ A}$, $di/dt \le 100 \text{ A}/\mu s$, $V_{DD} \le BV_{DSS}$, $T_{J} = +150^{\circ}C$



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V _{DSS} (@ T _{Jmax})	R _{DS(ON)} (MAX) @ 3 A
650 V	1.2 Ω





NDF06N60ZG, NDF06N60ZH TO-220FP CASE 221AH

ORDERING AND MARKING INFORMATION

See detailed ordering, marking and shipping information on page 6 of this data sheet.

THERMAL RESISTANCE

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3.6	°C/W
Junction-to-Ambient Steady State (Note 3)	$R_{\theta JA}$	50	

^{3.} Insertion mounted

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Characteristic	Test Conditions		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS					•	•	
Drain-to-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 1 mA		BV _{DSS}	600			V
Breakdown Voltage Temperature Co- efficient	Reference to 25°C, I _D = 1 mA		$\Delta BV_{DSS} / \Delta T_{J}$		0.6		V/°C
Drain-to-Source Leakage Current	25°C		I _{DSS}			1	μΑ
	$V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$	150°C				50	1
Gate-to-Source Forward Leakage	V _{GS} = ±20 V		I _{GSS}			±10	μΑ
ON CHARACTERISTICS (Note 4)							
Static Drain-to-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 3.0 \text{ A}$		R _{DS(on)}		0.98	1.2	Ω
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 100 \mu A$		V _{GS(th)}	3.0	3.9	4.5	V
Forward Transconductance	V _{DS} = 15 V, I _D = 3.0 A		9FS		5.0		S
DYNAMIC CHARACTERISTICS					•	•	•
Input Capacitance (Note 5)	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		C _{iss}	738	923	1107	pF
Output Capacitance (Note 5)			C _{oss}	90	106	125	
Reverse Transfer Capacitance (Note 5)			C _{rss}	15	23	30	
Total Gate Charge (Note 5)			Qg	15.5	31	47	nC
Gate-to-Source Charge (Note 5)	V 2001/ L 2014		Q _{gs}	3	6.3	9.5	
Gate-to-Drain ("Miller") Charge (Note 5)	V_{DD} = 300 V, I_{D} = 6.0 A, V_{GS} = 10 V		Q_{gd}	8	17	24.5	
Plateau Voltage			V _{GP}		6.4		V
Gate Resistance			R _g		3.2		Ω
RESISTIVE SWITCHING CHARACTERI	STICS						
Turn-On Delay Time			t _{d(on)}		13		ns
Rise Time	V _{DD} = 300 V, I _D = 6.0 A	,	t _r		17		1
Turn-Off Delay Time	V_{GS} = 10 V, R_{G} = 5 Ω		t _{d(off)}		30		1
Fall Time			t _f		28		1
SOURCE-DRAIN DIODE CHARACTER	ISTICS (T _C = 25°C unless otherv	vise noted))				
Diode Forward Voltage	I _S = 6.0 A, V _{GS} = 0 V		V_{SD}			1.6	V
Reverse Recovery Time	$V_{GS} = 0 \text{ V}, V_{DD} = 30 \text{ V}$ $I_S = 6.0 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$		t _{rr}		338		ns
Reverse Recovery Charge			Q _{rr}		2.0		μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Width ≤ 380 μs, Duty Cycle ≤ 2%.

5. Guaranteed by design.

TYPICAL CHARACTERISTICS

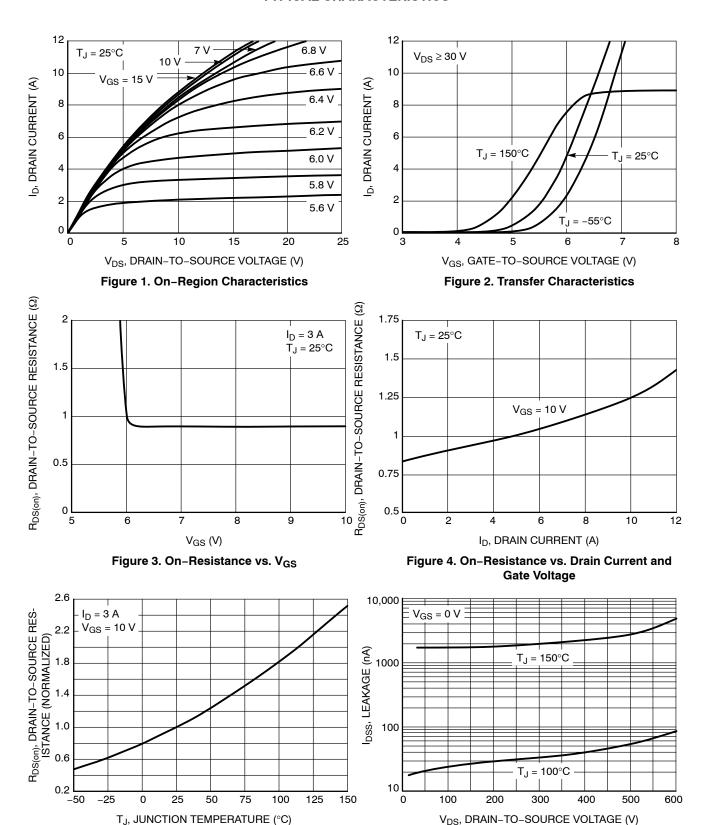


Figure 6. Drain-to-Source Leakage Current

vs. Voltage

Figure 5. On-Resistance Variation with

Temperature

TYPICAL CHARACTERISTICS

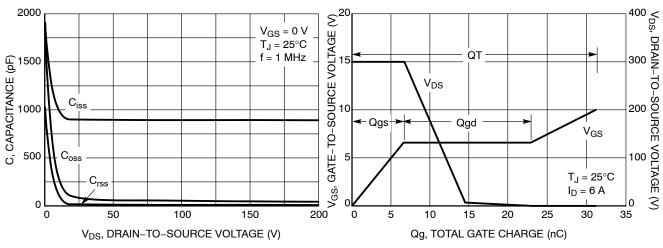


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

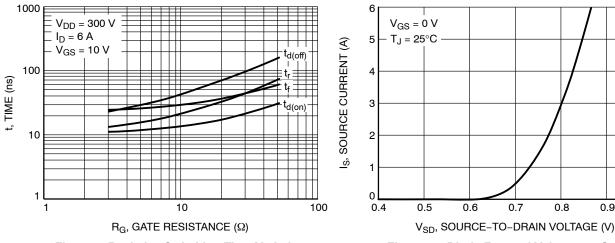


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

8.0

1.0

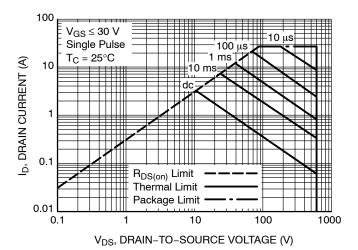


Figure 11. Maximum Rated Forward Biased Safe Operating Area for NDF06N60Z

TYPICAL CHARACTERISTICS

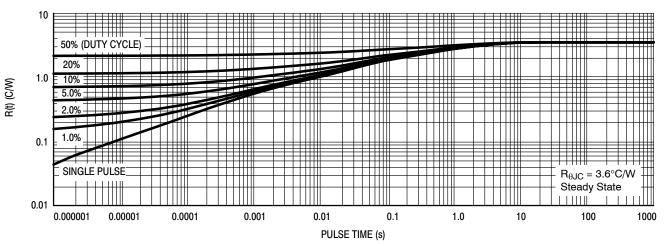


Figure 12. Thermal Impedance for NDF06N60Z

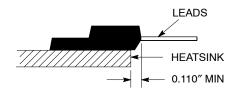


Figure 13. Mounting Position for Isolation Test

Measurement made between leads and heatsink with all leads shorted together.

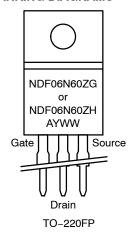
^{*}For additional mounting information, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ORDERING INFORMATION

Order Number	Package	Shipping [†]
NDF06N60ZG	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDF06N60ZH	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

MARKING DIAGRAMS

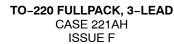


A = Location Code

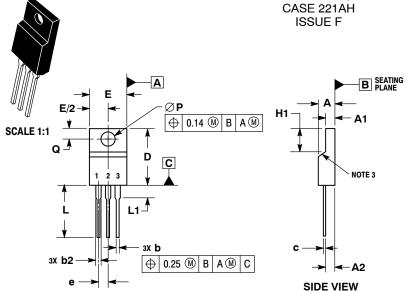
Y = Year

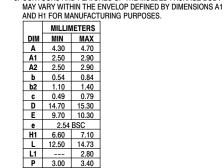
WW = Work Week

G, H = Pb-Free, Halogen-Free Package



DATE 30 SEP 2014

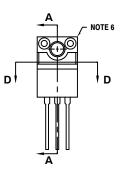


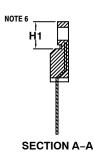


NOTES:

SECTION D-D

FRONT VIEW





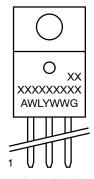
ALTERNATE CONSTRUCTION

GENERIC MARKING DIAGRAM*

 DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: MILLIMETERS.
3. CONTOUR UNCONTROLLED IN THIS AREA.

3. CONTOUR UNCONTROLLED IN THIS AREA.
4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH AND GATE PROTRUSIONS. MOLD FLASH AND GATE PROTRUSIONS NOT TO EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE TO BE MEASURED AT OUTERMOST EXTREME OF THE PLASTIC BODY.
5. DIMENSION b2 DOES NOT INCLUDE DAMBAR PROTRUSION. LEAD WIDTH INCLUDING PROTRUSION SHALL NOT EXCEED 2.00.
6. CONTOURS AND FEATURES OF THE MOLDED PACKAGE BODY.

MAY VARY WITHIN THE ENVEL OR DEFINED BY UNIENSIONS A1



= Assembly Location

WL = Wafer Lot

= Year

WW = Work Week

G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

STYLE 1:		STYLE 2:	
PIN 1.	MAIN TERMINAL 1	PIN 1.	CATHODE
2.	MAIN TERMINAL 2	2.	ANODE
3.	GATE	3.	GATE

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DESCRIPTION	TO-220 FULL PACK 3-1 FA	ΔD	PAGE 1 OF 1

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